

Machine Learning Framework for Impurity Level Prediction in Semiconductors

Arun Mannodi-Kanakkithodi⁺, Michael Toriyama⁺, Fatih G. Sen⁺, Michael J. Davis^{*}, Maciej P. Polak[○], Ryan Jacobs[○], Dane Morgan[○], Xiaofeng Xiang[□], Laura Jacoby[□], Robert Biegaj[□] and Maria K.Y. Chan⁺

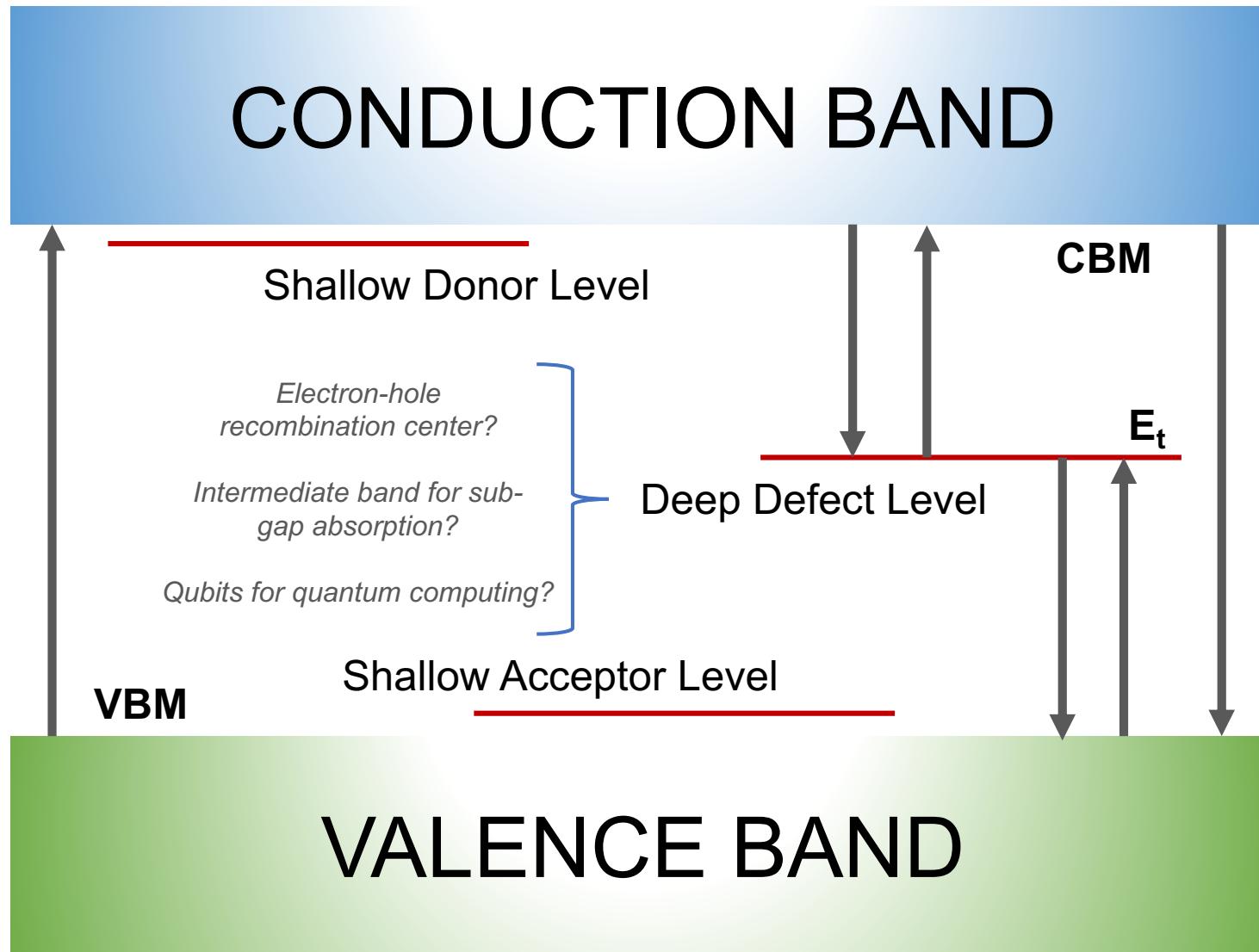
⁺Center for Nanoscale Materials, Argonne National Laboratory

^{*}Chemical Sciences and Engineering, Argonne National Laboratory

[○]Department of Materials Science and Engineering, University of Wisconsin-Madison

[□]Direct Capstone Program, University of Washington

Impurity Levels in Semiconductors



CHALLENGES

Experimental

- Sample preparation difficult with DLTS or CL.
- Difficult to assign observed levels to particular defect.

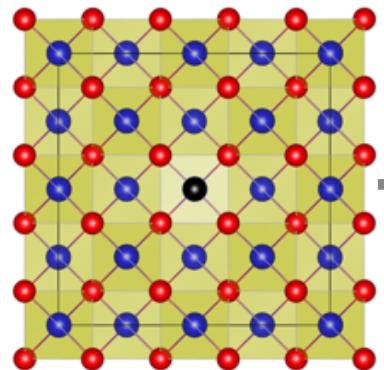
Density Functional Theory (DFT)

- Large supercells, charge states → expensive.
- Prior knowledge not utilized for new defect levels.

Predicting Impurity Behavior in Semiconductors

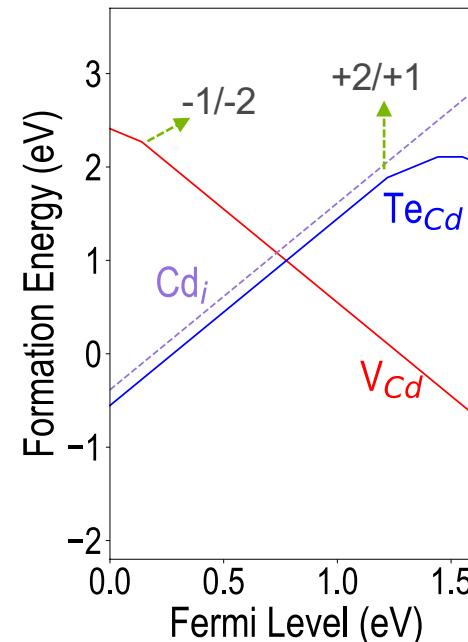
- "Computational Study of Pb Substitution in MAPbBr₃", *Chem. Mater.* (2019).
- "Machine-learned impurity level prediction for Cd chalcogenides", *npj Comput. Mater.* (2020).
- "Universal ML Framework for Impurity Level Prediction in Group IV, III-V & II-VI Semiconductors", *in prep.*
- "Accelerated Screening of Functional Atomic Impurities in Halide Perovskites using High-Throughput Computations and Machine Learning", *in prep.*

Semiconductor + impurity



Density Functional Theory

- $E^f(q) = E(D^q) - E(\text{bulk}) + \sum n_i \mu_i + q(E_F + E_{vbm}) + E_{\text{corr}}$
- Impurity levels: $\varepsilon(q_1/q_2) = [E^f(q_1) - E^f(q_2)] / (q_2 - q_1)$

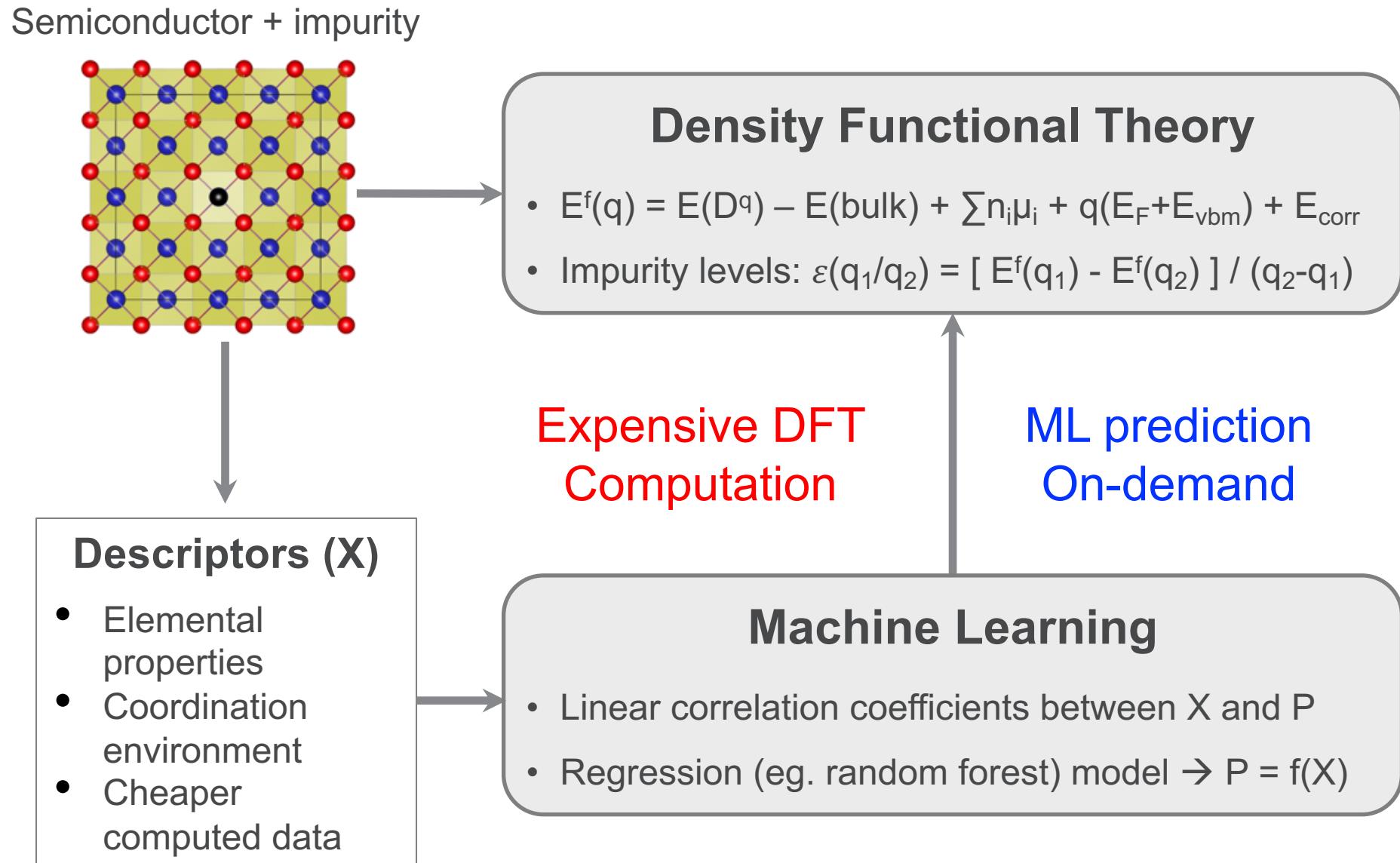


Impurity levels
 $\varepsilon(q_1/q_2)$:

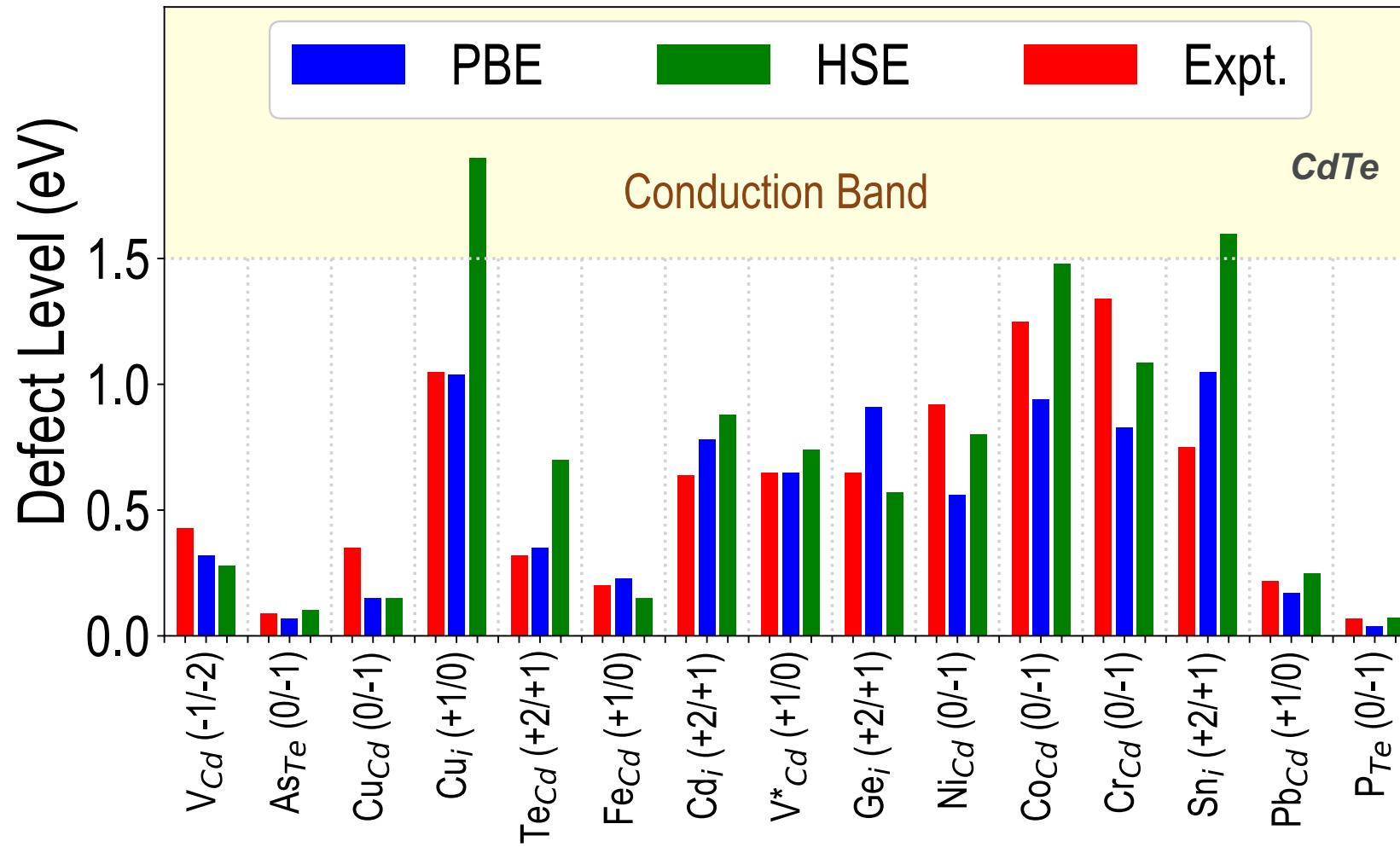
Fermi energies
(E_F) where defect
transitions from
one stable charge
state (q_1) to
another (q_2)

Predicting Impurity Behavior in Semiconductors

- "Computational Study of Pb Substitution in MAPbBr₃", *Chem. Mater.* (2019).
- "Machine-learned impurity level prediction for Cd chalcogenides", *npj Comput. Mater.* (2020).
- "Universal ML Framework for Impurity Level Prediction in Group IV, III-V & II-VI Semiconductors", *in prep.*
- "Accelerated Screening of Functional Atomic Impurities in Halide Perovskites using High-Throughput Computations and Machine Learning", *in prep.*



$\varepsilon(q_1/q_2)$: DFT vs Experiments



Root mean square
error (RMSE)
between DFT (PBE)
and experiments
= 0.22 eV

*ML models with
similar accuracy
can replace DFT
computations and
lead to accelerated
screening.*

Steps Involved in Training a Material → Property Regression Model

1. READ DATA: Labels, computed properties, descriptors.
2. SELECT ML TECHNIQUE: Random Forest / Kernel Ridge / LASSO / etc.
3. TRAIN DEFAULT MODEL: With a (for eg.) 70-30 training-test split, train a model using chosen technique.
4. HYPERPARAMETER OPTIMIZATION: Improve model by tuning every hyperparameter to minimize test prediction error.
5. CROSS-VALIDATION: Divide training data into n folds, tune hyperparameters to minimize cross-validation test error.
6. LEARNING CURVES: Model prediction performance vs training set size.
7. DEPLOY BEST MODEL: Make new predictions and discovery.

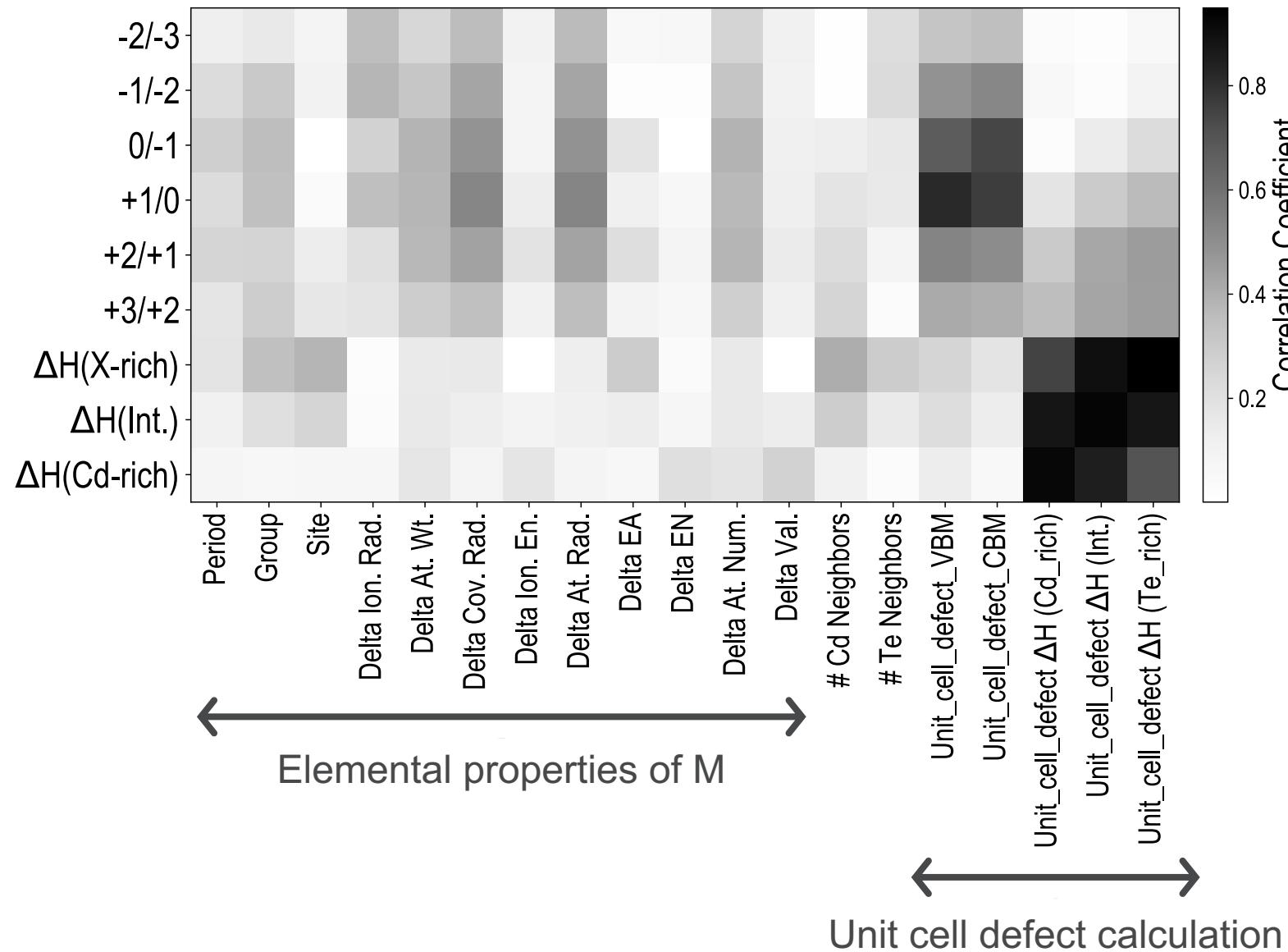
DFT Dataset for Machine Learning

CdX	Doping Site	M	$\Delta H(\text{Cd-rich})$	$\Delta H(\text{Mod})$	$\Delta H(\text{Te-rich})$	(+3/+2)	(+2/+1)	(+1/0)	(0/-1)	(-1/-2)	(-2/-3)
CdTe	M_Te	N	2.09	2.48	2.88	-0.97	-0.67	-0.40	-0.08	1.44	1.90
CdTe	M_Te	O	1.17	1.17	1.43	-0.91	-0.65	-0.33	0.95	1.37	2.11
CdTe	M_i_Te_site	Rh	3.46	3.93	4.88	-0.52	0.05	0.56	1.12	1.83	2.14
CdTe	M_Te	Re	6.75	7.22	7.70	0.68	-0.49	-1.05	0.61	1.72	2.18
CdSe	M_Se	Si	2.59	3.27	5.21	-0.64	-0.33	0.30	0.70	1.10	2.21
CdTe	M_Cd	Be	0.58	0.46	0.34	-0.92	-0.65	-0.32	1.40	1.84	2.22
CdTe	M_i_Cd_site	F	1.72	1.48	1.24	-0.85	-0.56	-0.29	0.03	1.77	2.23
CdTe	M_i_Te_site	F	2.61	2.38	2.14	-0.84	-0.51	-0.22	0.09	1.80	2.26
CdSe	M_Cd	Cu	2.49	1.23	1.05	-0.88	-0.51	-0.14	0.36	1.79	2.33
CdSe	M_Se	Os	5.88	6.53	7.17	-0.55	-0.55	0.05	1.44	1.90	2.36
CdSe	M_i_Cd_site	F	1.95	1.63	1.31	-0.83	-0.51	-0.21	0.12	1.82	2.38
CdTe	M_i_Cd_site	Hg	1.78	1.47	1.76	-0.65	-0.15	0.29	1.66	2.06	2.42
CdTe	M_i_old	Cu	2.50	1.94	2.22	-0.74	-0.40	1.26	1.72	2.08	2.43
CdSe	M_i_Se_site	Cl	3.68	3.36	3.03	-0.65	-0.32	0.05	0.38	1.94	2.51
CdTe	M_Cd	Sr	1.06	1.06	1.06	-0.64	-0.41	-0.10	1.66	2.11	2.52
CdS	M_i_S_site	S	5.23	4.57	3.91	-0.06	-0.05	0.78	1.13	1.59	2.69
CdS	M_i_Cd_site	S	4.81	4.15	3.49	-0.56	-0.27	0.56	1.02	1.50	2.71
CdS	M_Cd	O	7.52	6.22	5.56	-0.87	-0.30	0.10	0.47	2.11	2.75
CdS	M_i_old	S	4.65	3.99	3.33	-0.65	0.83	0.83	1.48	1.95	2.75
CdSe	M_i_Se_site	Pd	2.22	1.58	2.02	-0.62	-0.19	0.27	1.56	2.09	2.89
CdS	M_Cd	S	6.04	4.73	3.42	-0.80	0.46	0.83	1.32	2.32	2.94
CdSe	M_Cd	Pb	0.76	0.73	0.74	-0.68	-0.16	0.34	1.67	2.19	2.97
CdS	M_i_old	Pt	3.03	2.38	3.25	-0.43	0.23	0.72	1.98	2.57	3.38
CdS	M_S	Se	0.19	0.20	0.21	-0.77	-0.42	-0.12	1.95	2.53	3.39

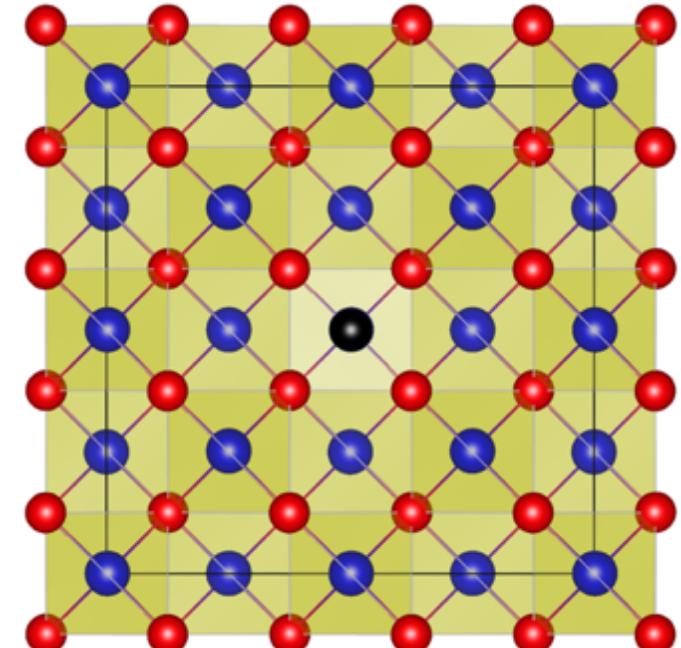
Dataset 1: Formation Enthalpies (ΔH) → 945 impurities → **945 points** (each)

Dataset 2: Charge Transition Levels ($\varepsilon(q_1/q_2)$) → 381 impurities → **2286 points** (combined)

Correlation between descriptors & properties



DATASET: 381 impurities in CdTe, CdSe and CdS.



→ unit cell defect calculation descriptors

The image part with relationship ID rld36 was not found in the file.

Descriptors for Machine Learning

CdX	Doping Site	M	Delta Ion. En.	Delta At. Rad.	Delta EN	Delta Val.	...	Unit_cell_def CBM	Unit_cell_def $\Delta H(\text{Mod})$	Unit_cell_def $\Delta H(\text{X-rich})$
CdTe	M_Te	N	-347.5	0.061	-0.71	-1		1.156	1.048	0.812
CdTe	M_Te	O	-371.9	0.411	-0.76	-1		1.316	1.173	1.083
CdTe	M_i_Te_site	Rh	-448.9	0.861	-0.87	-1		1.647	1.942	1.965
CdTe	M_Te	Re	-464.7	0.991	-0.87	2		2.140	2.326	2.481
CdSe	M_Se	Si	-492	1.181	-0.9	-1		2.000	3.000	3.000
CdTe	M_Cd	Be	31.7	-0.369	-0.12	0		2.718	0.770	0.651
CdTe	M_i_Cd_site	F	-130	0.111	-0.38	0		2.907	0.113	0.114
CdTe	M_i_Te_site	F	-277.9	0.481	-0.69	0		2.995	0.864	0.865
CdSe	M_Cd	Cu	-318.2	0.661	-0.74	0		2.995	1.276	1.277
CdSe	M_Se	Os	-364.8	0.731	-0.8	0		2.897	1.807	1.808
CdSe	M_i_Cd_site	F	-67.1	-0.509	0.35	1		3.300	3.320	2.846
CdTe	M_i_Cd_site	Hg	-290.1	-0.059	-0.08	1		3.547	0.954	1.214
CdTe	M_i_old	Cu	-288.9	-0.079	0.12	1		3.032	0.757	0.856
CdSe	M_i_Se_site	Cl	-309.4	0.171	0.09	1		3.327	0.723	0.920
CdTe	M_Cd	Sr	-278.4	0.221	0.35	1		2.854	0.999	0.796
CdS	M_i_S_site	S	218.7	-0.579	0.86	2		3.506	5.499	5.025
CdS	M_i_Cd_site	S	-81.3	-0.169	0.21	2		3.408	1.755	1.281
CdS	M_Cd	O	-105.6	-0.119	0.32	2		3.541	0.897	0.737
CdS	M_i_old	S	-159.1	0.131	0.27	2		3.491	1.076	1.077
CdSe	M_i_Se_site	Pd	-152.2	0.261	0.64	2		3.457	0.980	0.981
CdS	M_Cd	S	534.6	-0.569	1.35	3		2.140	4.523	3.970
CdSe	M_Cd	Pb	144	-0.209	0.5	3		2.945	2.574	2.045
CdS	M_i_old	Pt	79.3	-0.099	0.47	3		3.116	1.953	1.502
CdS	M_S	Se	-34	0.101	0.36	3		3.375	4.104	4.342

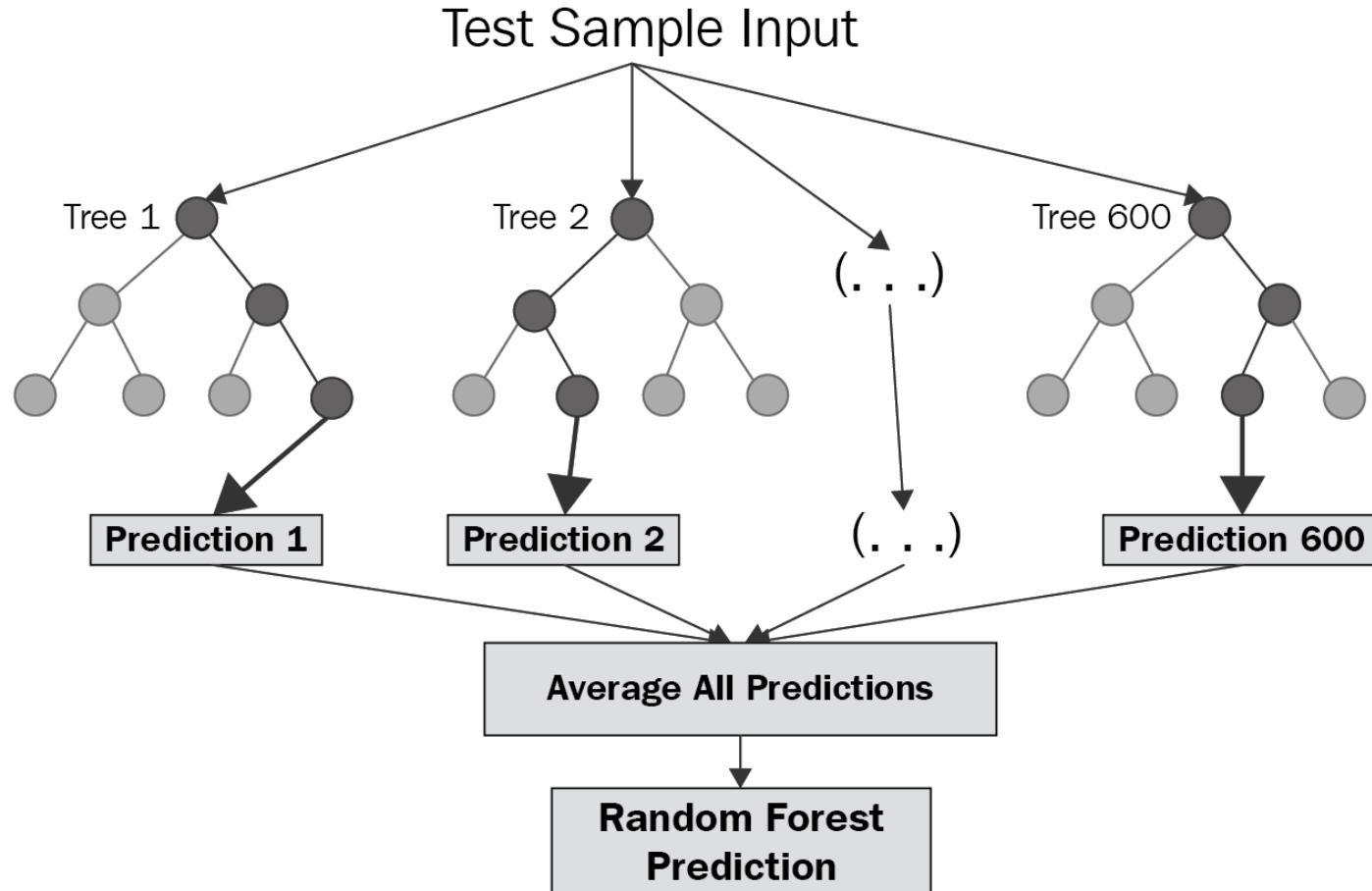
Descriptor Set 1: Elemental Properties (14 features)

Descriptor Set 2: Unit Cell Defect Properties (5 features)

Descriptor Set 3: Elemental + Unit Cell (19 features)

 The image part with relationship ID rId36 was not found in the file.

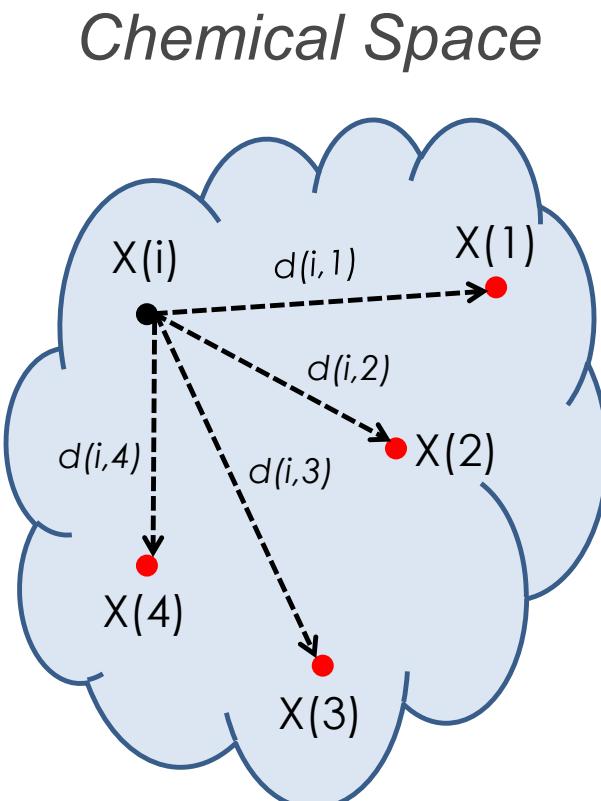
Random Forest Regression



<https://towardsdatascience.com/random-forest-and-its-implementation-71824ced454f>

The image part with relationship ID rId36 was not found in the file.

Kernel Ridge Regression



Similarity-based regression

Measure of Similarity: Euclidean Distance

$$d(i,j) = \sqrt{(x_{i1} - x_{j1})^2 + \dots + (x_{im} - x_{jm})^2}$$

Property = Weighted sum of Gaussians

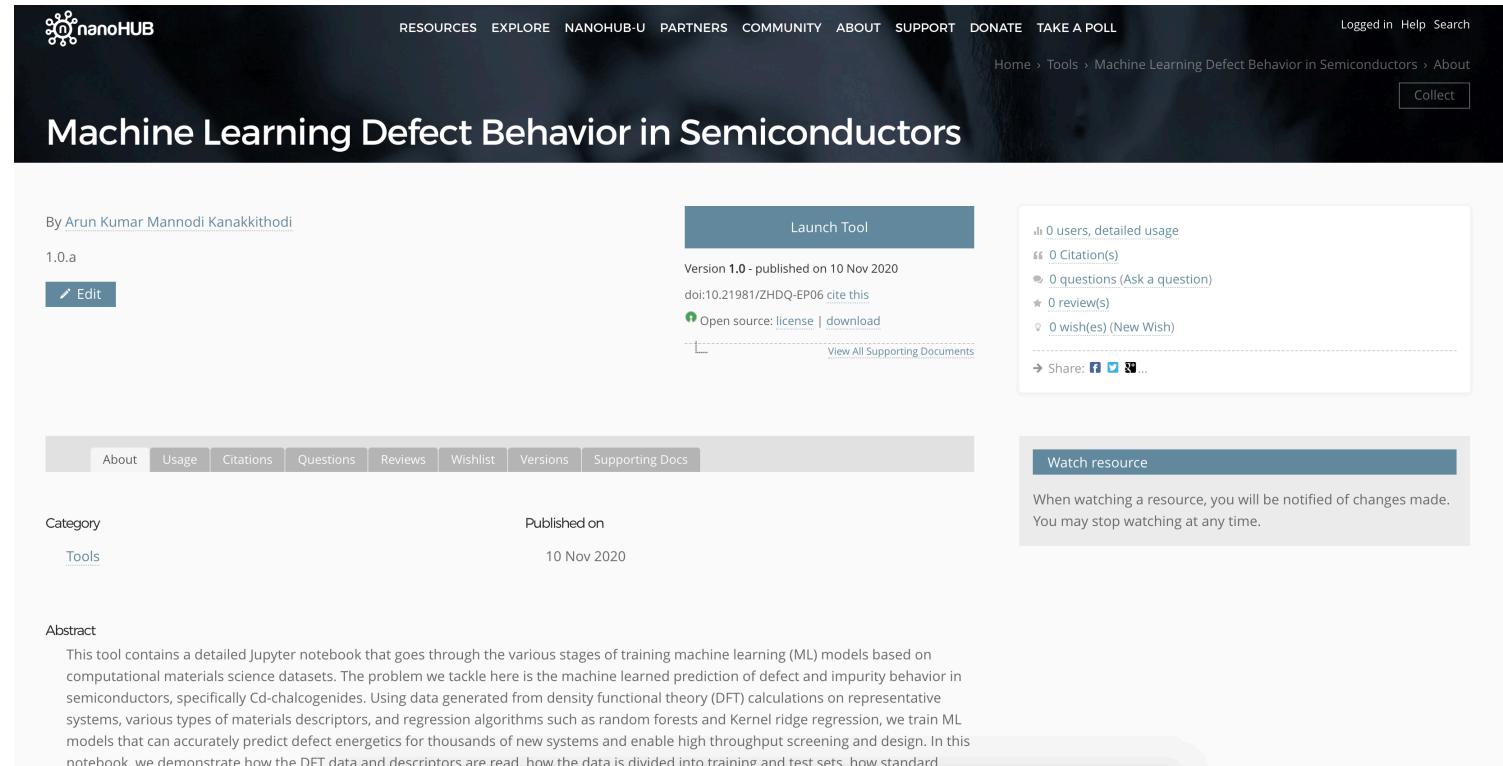
$$f(i) = \sum_{k=1}^N a_k \cdot \exp\left(-\frac{1}{2\sigma^2} \cdot [d(i, i_k)]^2\right)$$

A. Mannodi-Kanakkithodi et al., *Sci. Rep.* **2016**.
T. D. Huan et al., *Phys. Rev. B*, **2015**.

The image part with relationship ID rld36 was not found in the file.

Launching the Jupyter tool on Nanohub

- Login to your account on Nanohub.
- Go to the following link:
<https://nanohub.org/resources/mldefect/>
- Click on “Launch Tool”; it may take a minute or so to load.
- You should be able to see the following Jupyter notebook.



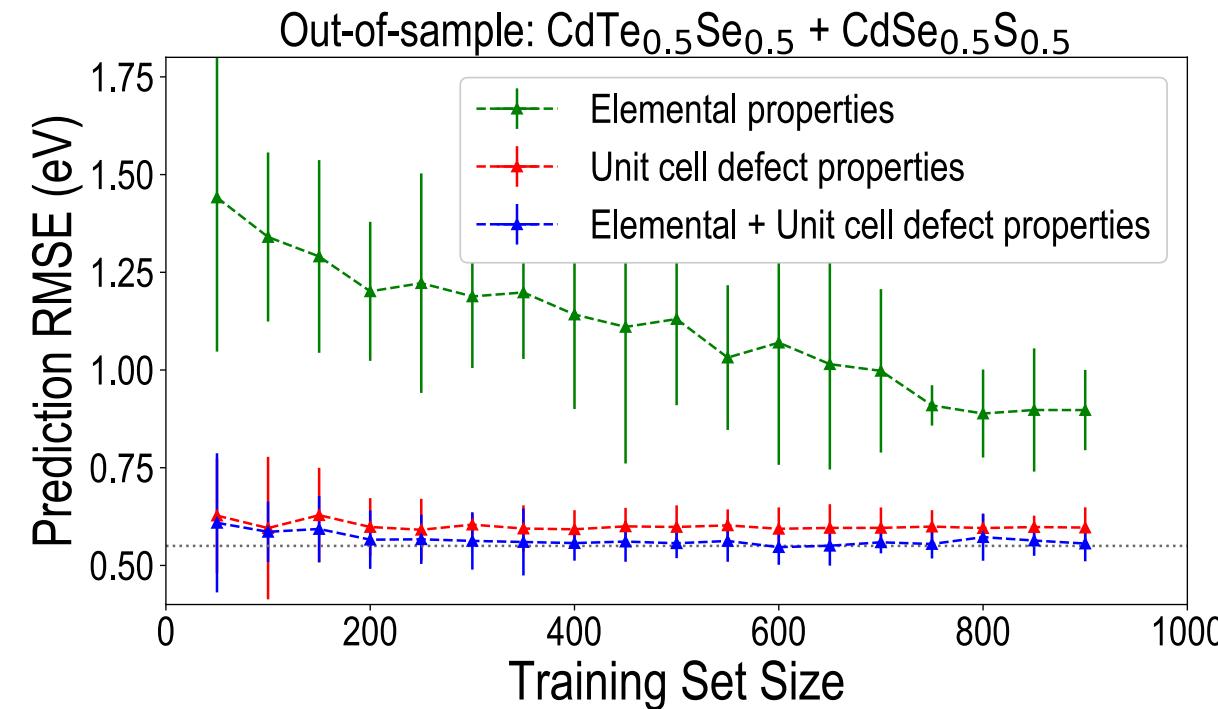
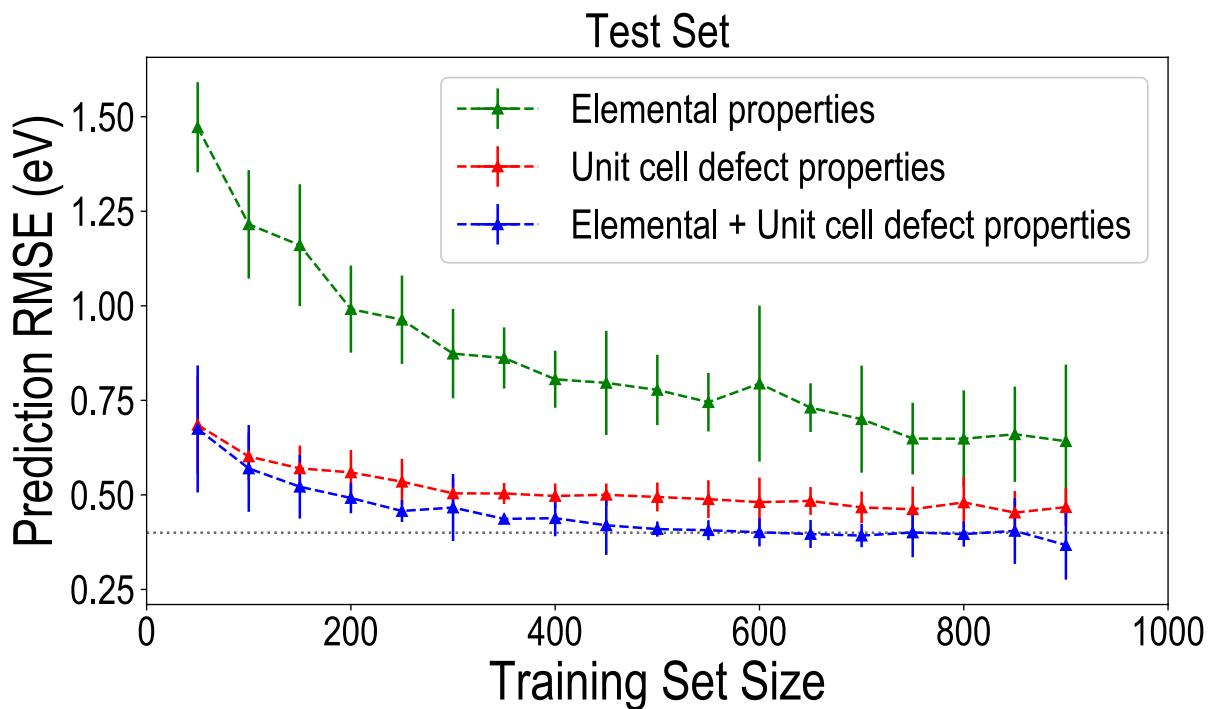
The screenshot shows a resource page on the nanohub.org website. The title is "Machine Learning Defect Behavior in Semiconductors". The page includes a "Launch Tool" button, version information (Version 1.0 published on 10 Nov 2020), and a "Watch resource" button. The abstract describes a Jupyter notebook for training ML models on computational materials science datasets, specifically Cd-chalcogenides.

Arun Kumar Mannodi Kanakkithodi (2020), "Machine Learning Defect Behavior in Semiconductors," <https://nanohub.org/resources/mldefect>.
(DOI: 10.21981/ZHDQ-EP06).

 The image part with relationship ID rId36 was not found in the file.

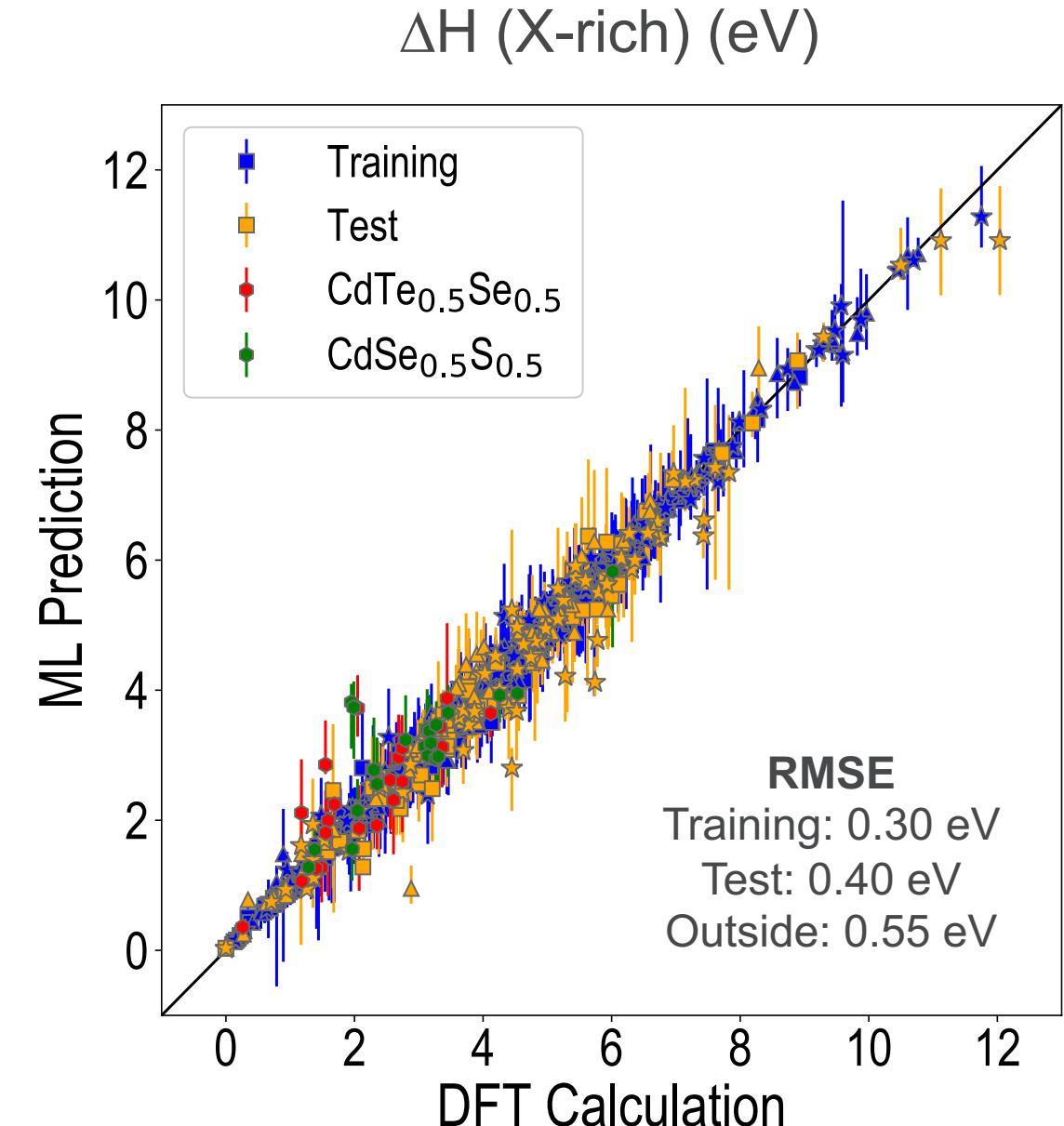
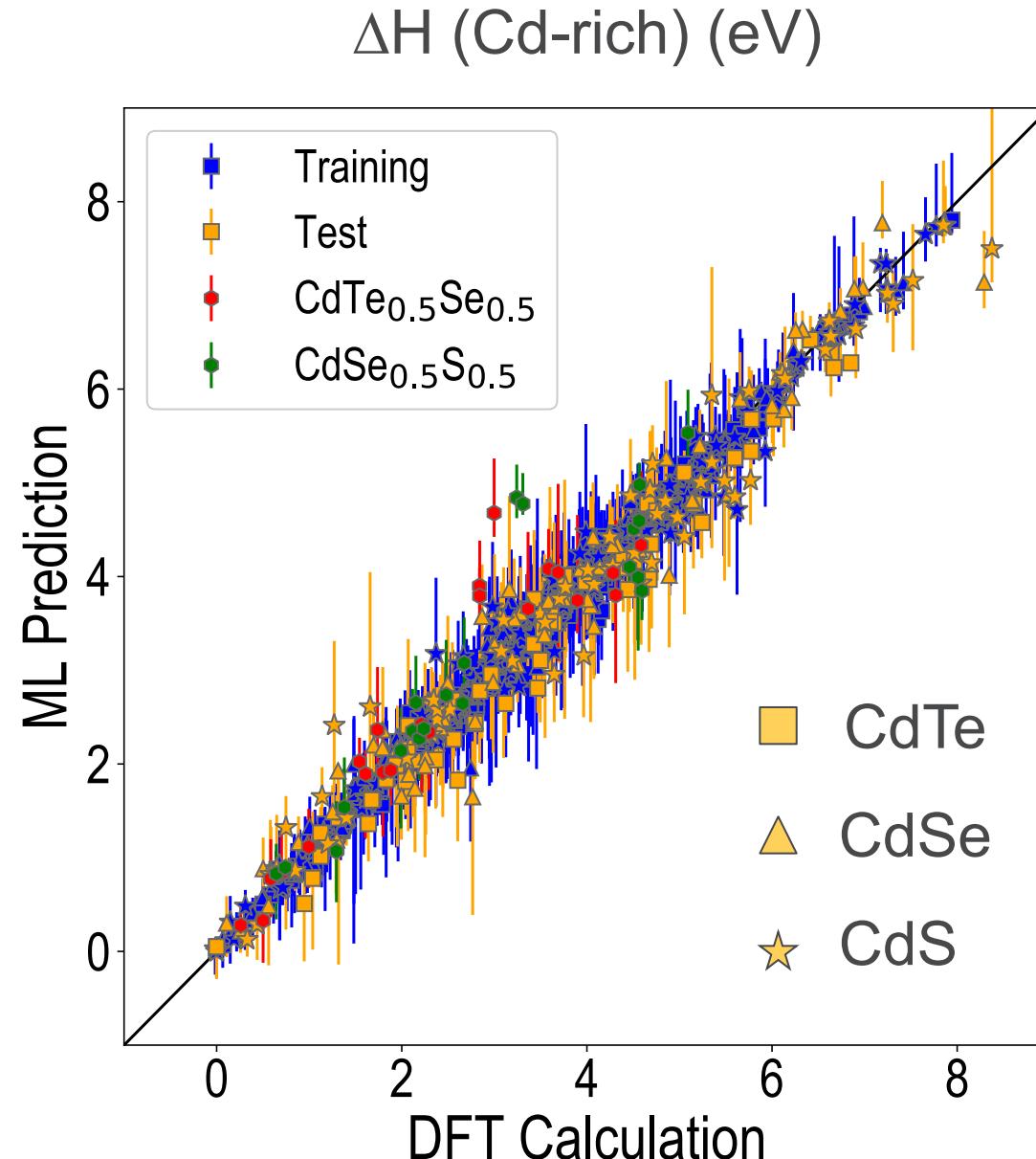
Random Forest: Formation Enthalpy

Models trained for ΔH (Cd-rich) on CdTe+CdSe+CdS data



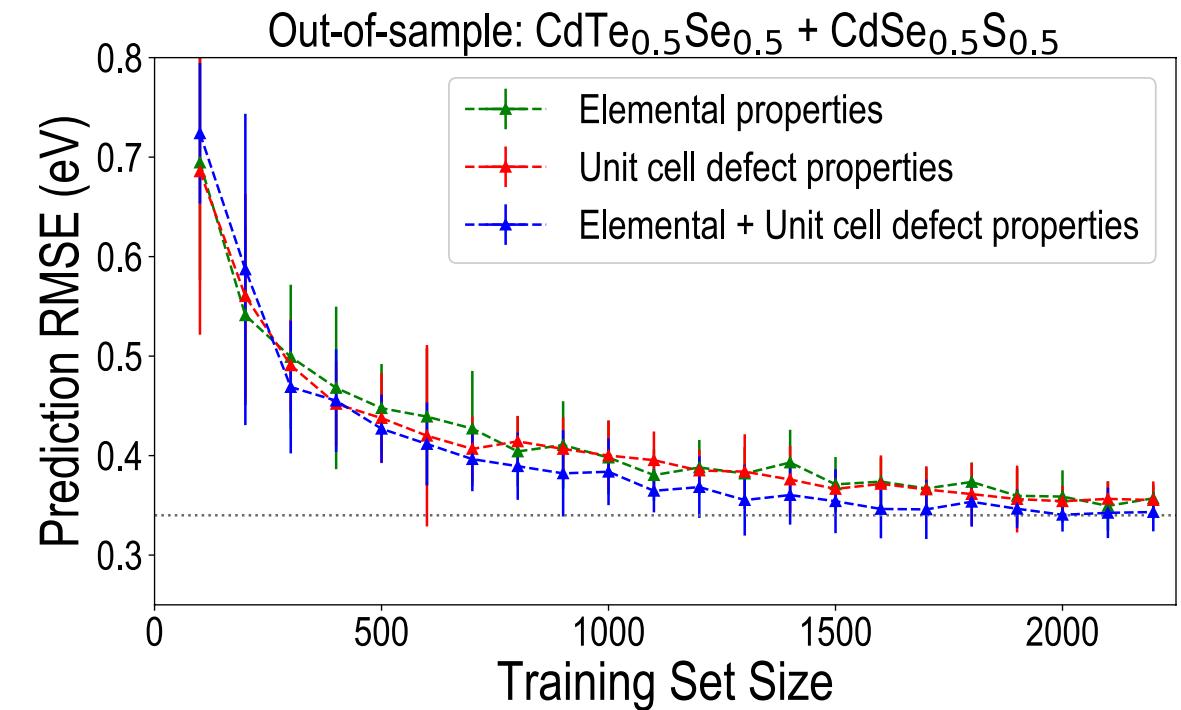
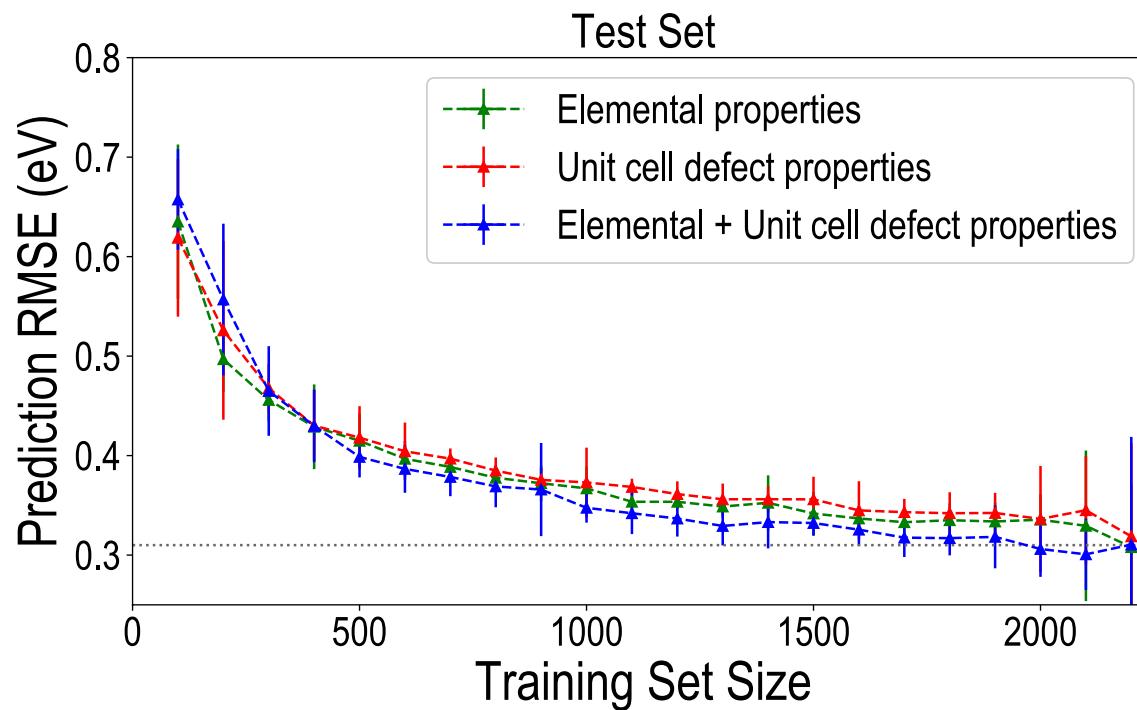
Elemental properties + unit cell defect properties lead to best models.

Random Forest: Formation Energy



Random Forest: Impurity Levels

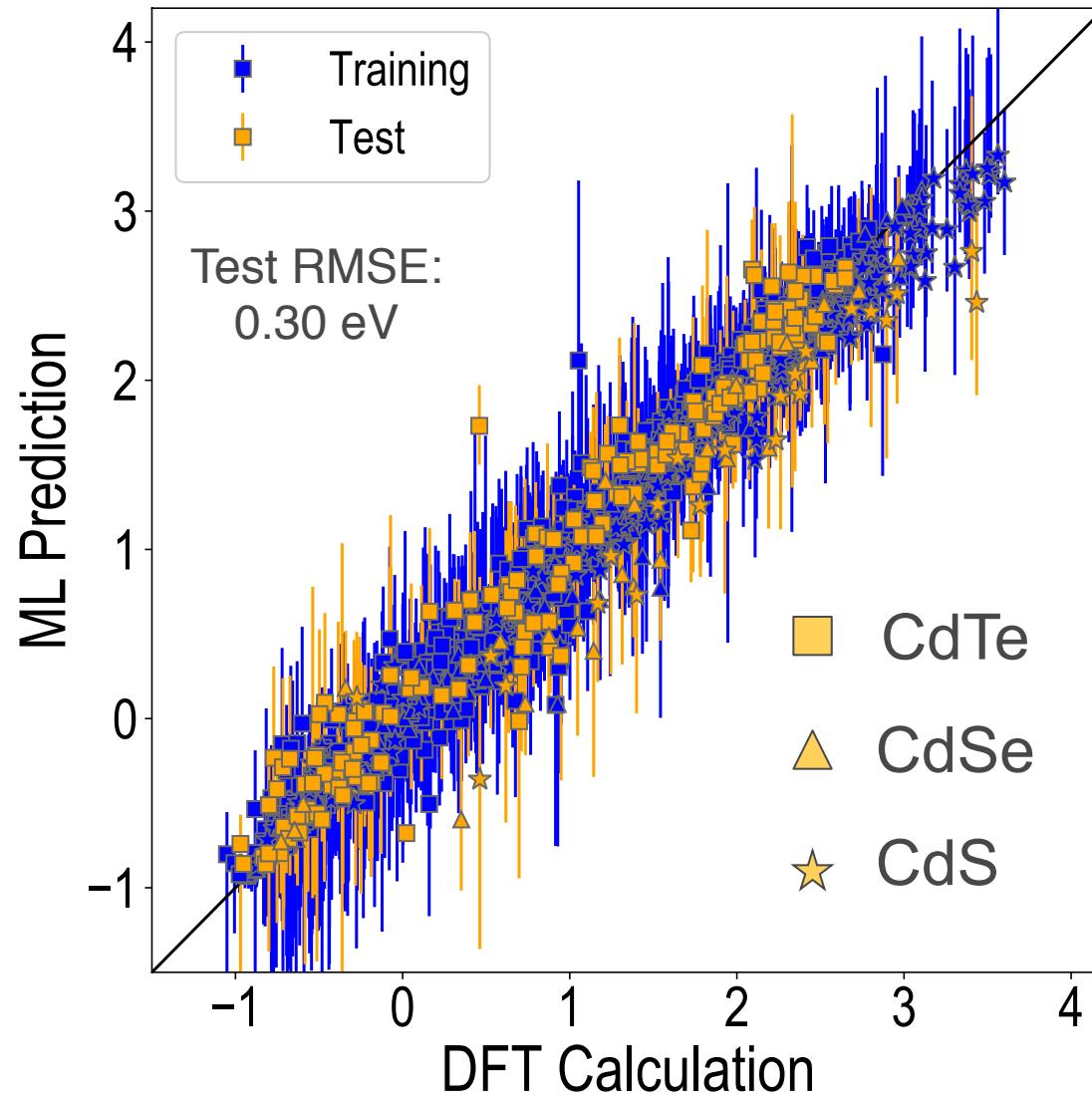
Models trained for $\varepsilon(q_1/q_2)$ on CdTe+CdSe+CdS data



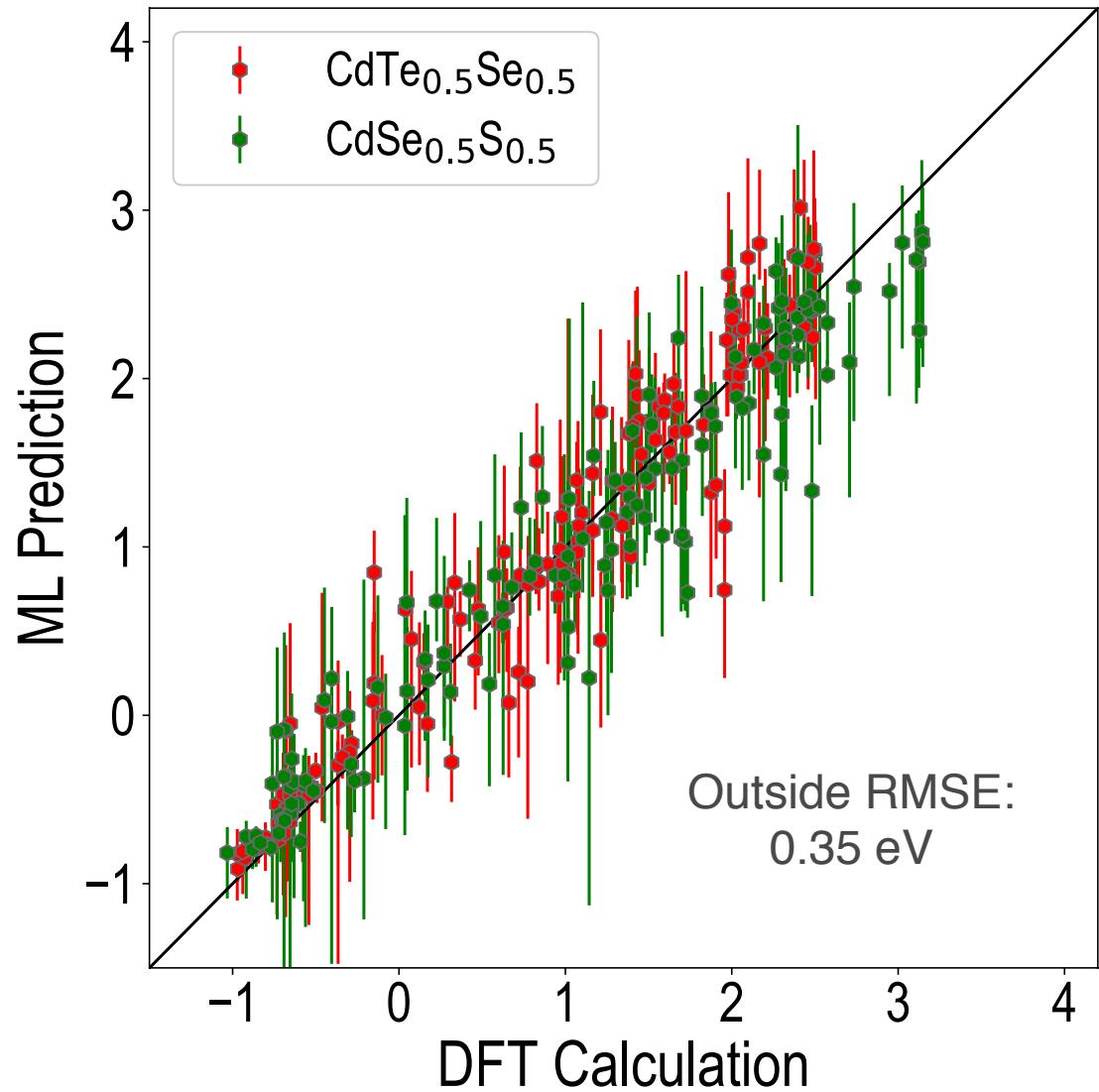
Elemental properties + unit cell defect properties lead to best models.

Random Forest: Transition Levels

RF Model to predict $\varepsilon(q_1/q_2)$ (eV)

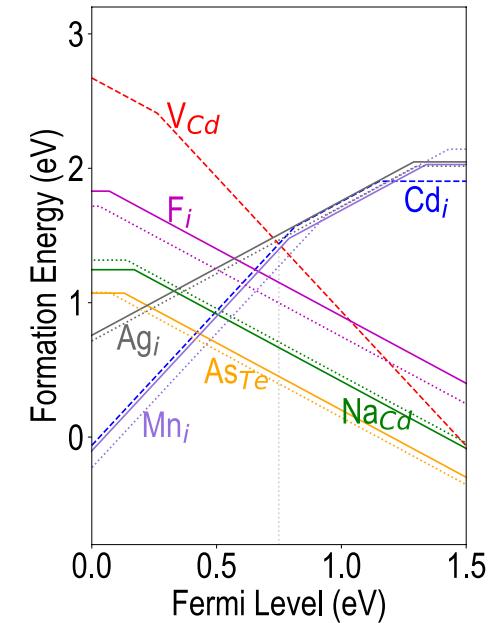


Out-of-sample prediction

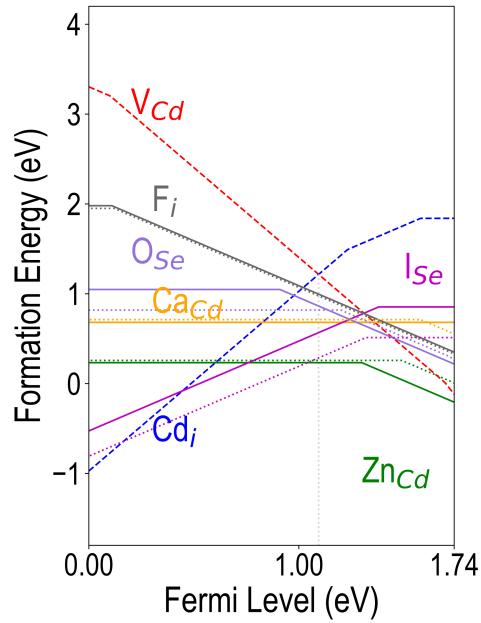


Impurity Formation Energies: DFT vs ML

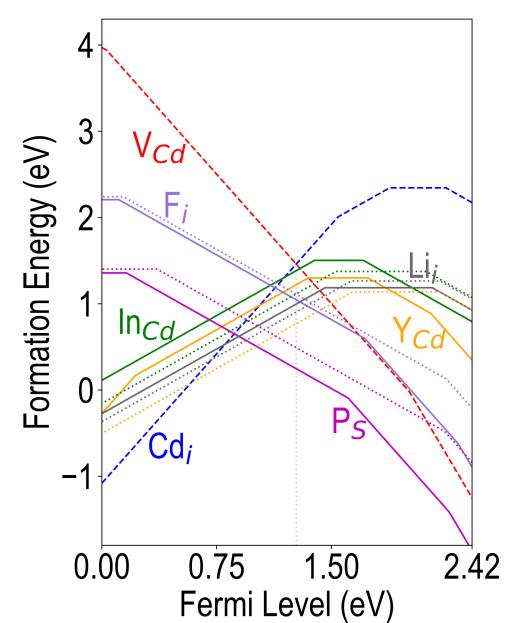
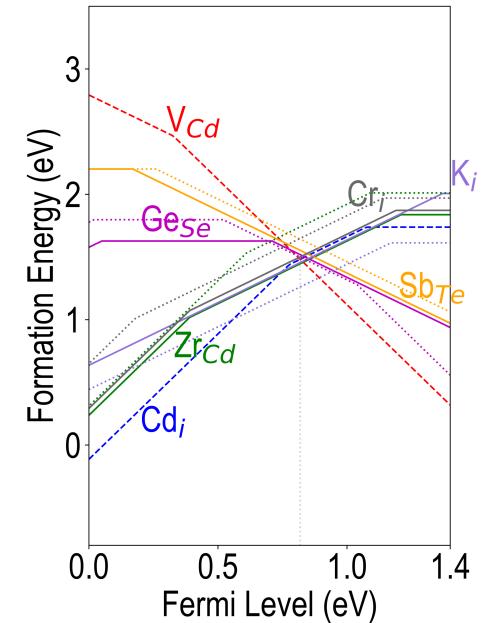
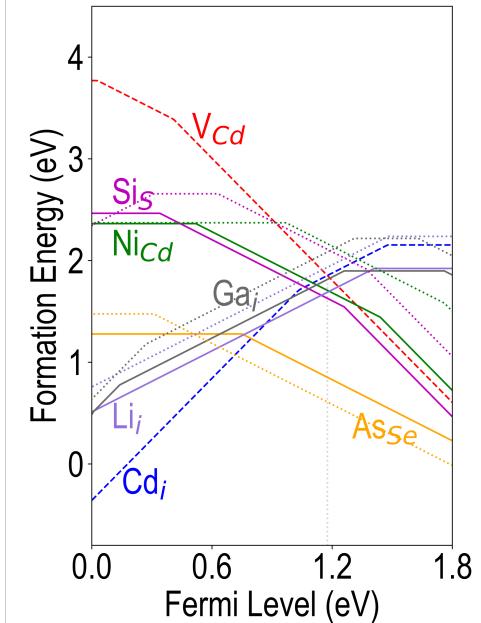
(a) CdTe



(b) CdSe



(c) CdS

(d) CdTe_{0.5}Se_{0.5}(e) CdSe_{0.5}S_{0.5}

ML models trained on dataset of 381 impurities in CdTe, CdSe & CdS are used to predict complete formation energies for 1827 impurities in 5 compounds; in theory applicable to any impurity in any Cd-Te-Se-S compound.

The image part with relationship ID rld36 was not found in the file.

Extensions of current work

New semiconductors, impurity atoms, structures (Wurtzite vs ZB)

A	B
Cd	O
Zn	S
	Se
	Te

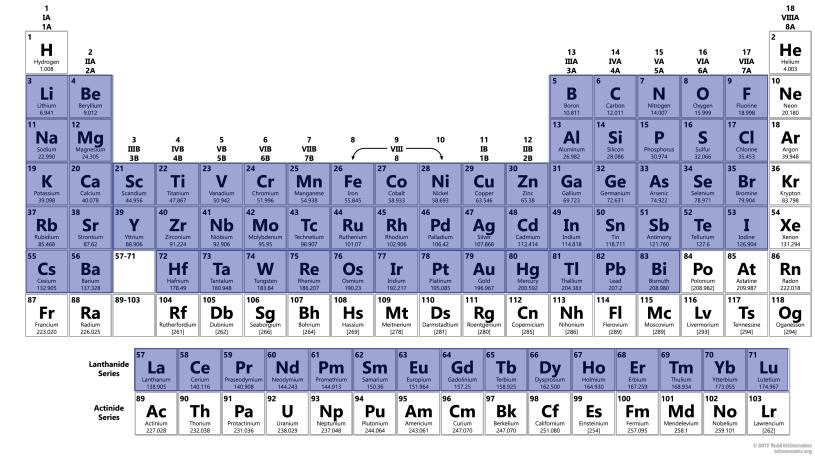
8 candidates

A	B
B	N
Al	P
Ga	As
In	Sb

16 candidates

A	B
C	C
Si	Si
Ge	Ge
Sn	Sn

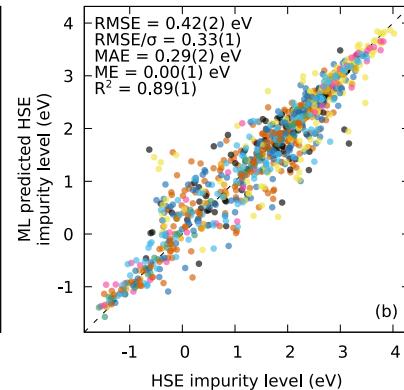
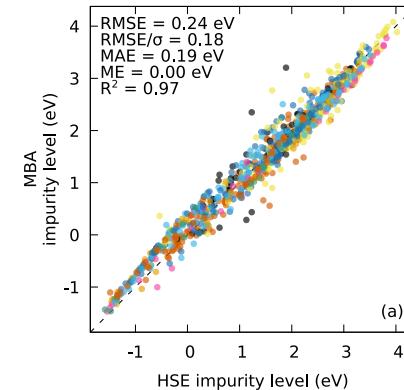
10 candidates



A.M.K et al., *in prep.*

Advanced theory: Modified band alignment (MBA) & HSE

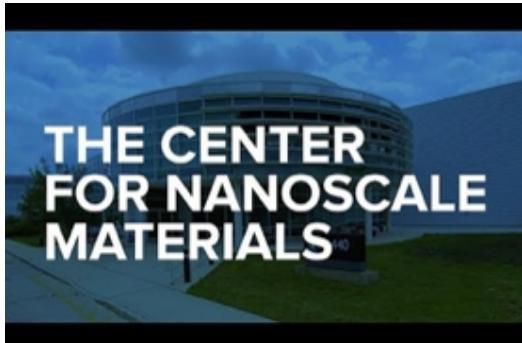
MBA vs HSE



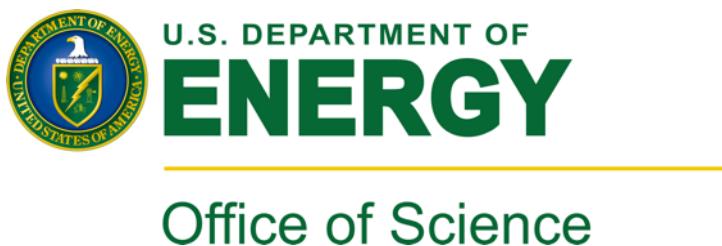
Acknowledgements

Argonne LDRD: Office of Science #DE-AC02-06CH11357

EERE PVRD: SunShot program #DOE DEEE005956.



National Energy Research
Scientific Computing Center



CONTACT: mannodiarun@anl.gov

The image part with relationship ID rld36 was not found in the file.

THANK YOU